



FOR IMMEDIATE RELEASE

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**Aehr Test Systems to Announce Second Quarter Fiscal 2017 Financial Results
on January 5, 2017**

Fremont, CA (December 22, 2016) – Aehr Test Systems (NASDAQ: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, today announced that it will report financial results for its second quarter of fiscal 2017 ended November 30, 2016 on Thursday, January 5, 2017 following the close of the market. The Company will host a conference call and webcast at 5:00 p.m. Eastern time to discuss the results.

What: Aehr Test Systems second quarter fiscal 2017 financial results conference call

When: Thursday, January 5th at 5:00 p.m. Eastern Time (2:00 p.m. PT)

Dial in Number: To access the live call, dial **888-239-5343** (US and Canada) or **913-312-1448** (International) and give the participant passcode **7947996**.

Webcast: To access the live webcast, please visit the investor relations section at www.aehr.com.

Call Replay: A phone replay of the call will be available approximately two hours following the end of the call through 8:00 p.m. ET on Thursday, January 12, 2017. To access the replay dial-in information, please click [here](#).

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS™ and FOX™ families of test and burn-in systems and WaferPak contactors. The ABTS systems are used in production and qualification testing of packaged parts for both low-power and high-power logic as well as memory devices. The FOX family of systems includes single and multi-wafer full wafer contact test and burn-in systems used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The WaferPak contactor contains a unique full wafer probe card capable of testing wafers up to 300mm that enables IC manufacturers to perform test and burn-in of full wafers on Aehr Test FOX systems. For more information, please visit Aehr Test's website at www.aehr.com.

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